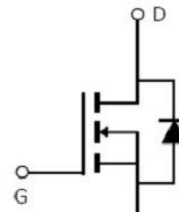


V_{DSS}	150V
$R_{DS(on)}$	4.4m (typ.)
I_D	150A



Advanced MOSFET process technology
 Special designed for PWM, load switching and
 general purpose applications
 Ultra low on-resistance with low gate charge
 Fast switching and reverse body recovery
 150 operating temperature



It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

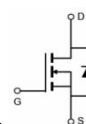
$I_D @ T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	150	A
I_{DM}	Pulsed Drain Current	600	
$P_D @ T_C = 25^\circ\text{C}$	Power Dissipation	312	W
V_{DS}	Drain-Source Voltage	150	V
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy @ $L=0.5\text{mH}$	1108	mJ
$T_J \quad T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ\text{C}$

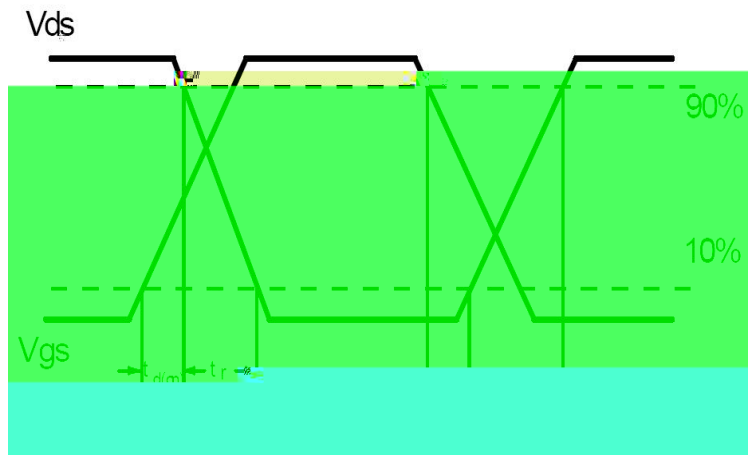
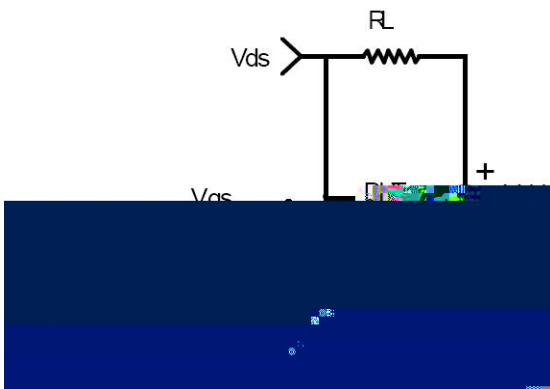
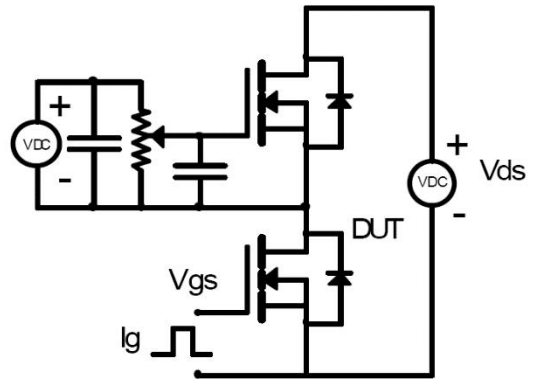
R_{JC}	Junction-to-case	—	0.4	/W
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@ $T_A=25$ unless otherwise specified

$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	150	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	4.4	6	m	$V_{GS}=10V, I_D=30A$
$V_{GS(th)}$	Gate threshold voltage	2	—	4	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
I_{DSS}	Drain-to-Source leakage current	—	—	1	μA	$V_{DS} = 150V, V_{GS} = 0V$
I_{GSS}	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 20V$
		—	—	-100		$V_{GS} = -20V$
Q_g	Total gate charge	—	80	—	nC	$I_D = 20A,$ $V_{DS}=75V,$ $V_{GS} = 10V$
Q_{gs}	Gate-to-Source charge	—	30	—		
Q_{gd}	Gate-to-Drain("Miller") charge	—	15	—		
$t_{d(on)}$	Turn-on delay time	—	34	—	ns	$V_{GS}=10V,$ $R_{GEN}=3$ $R_L=1.07$ $V_{DS}=75V$
t_r	Rise time	—	10	—		
$t_{d(off)}$	Turn-Off delay time	—	38	—		
t_f	Fall time	—	4	—		
C_{iss}	Input capacitance	—	6197	—	pF	$V_{GS} = 0V$ $V_{DS} = 100V$ $f = 1MHz$
C_{oss}	Output capacitance	—	560	—		
C_{rss}	Reverse transfer capacitance	—	20	—		

I_S	Continuous Source Current (Body Diode)	—	—	150	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode)	—	—	600	A	
V_{SD}	Diode Forward Voltage	—	—	1.2	V	$I_S=30A, V_{GS}=0V$
t_{rr}	Reverse Recovery Time	—	120	—	ns	$I_S=15A, di/dt=100A/us$
Q_{rr}	Reverse Recovery Charge	—	250	—	nC	

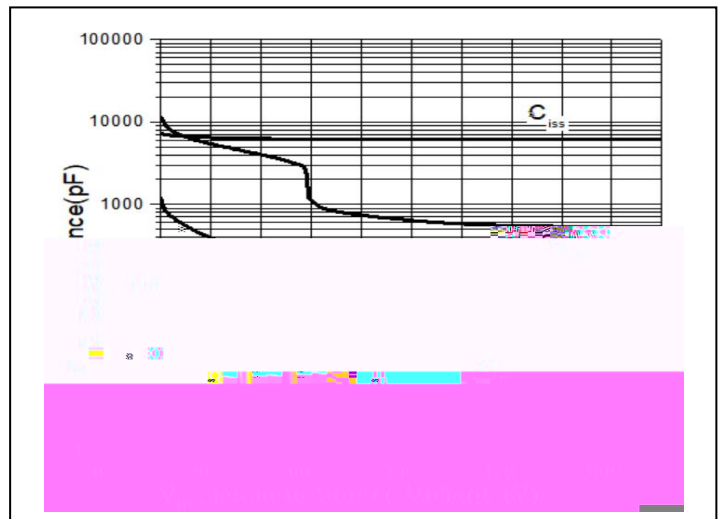
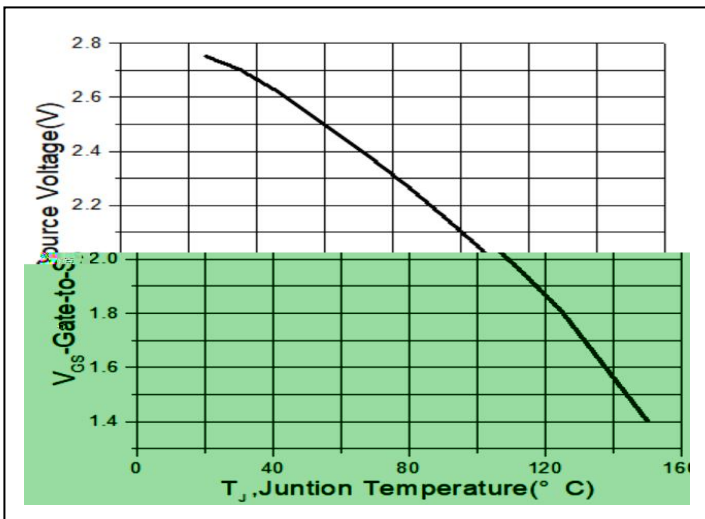
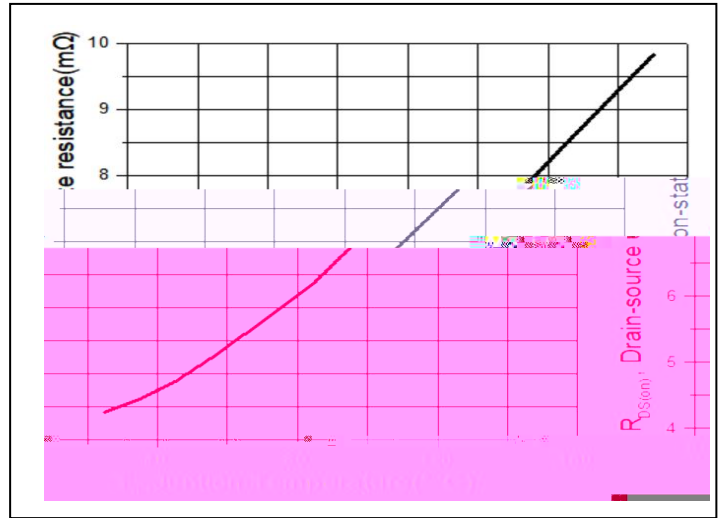
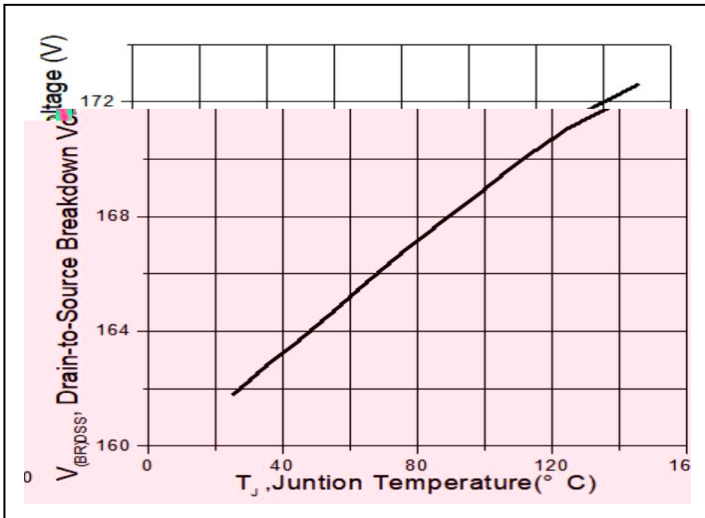
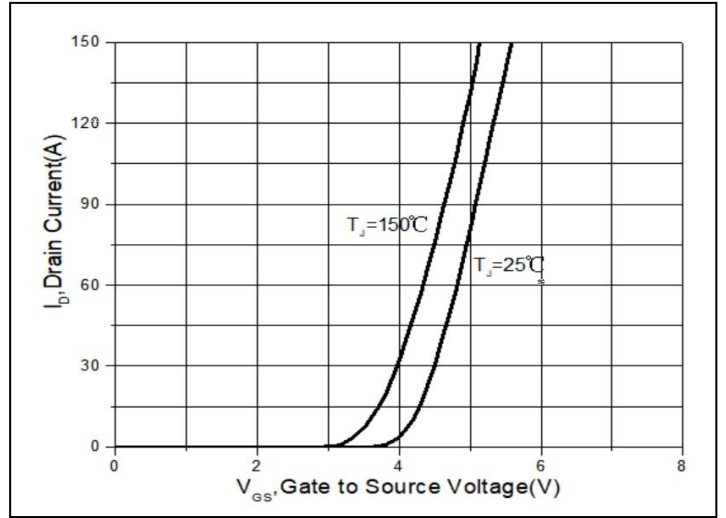
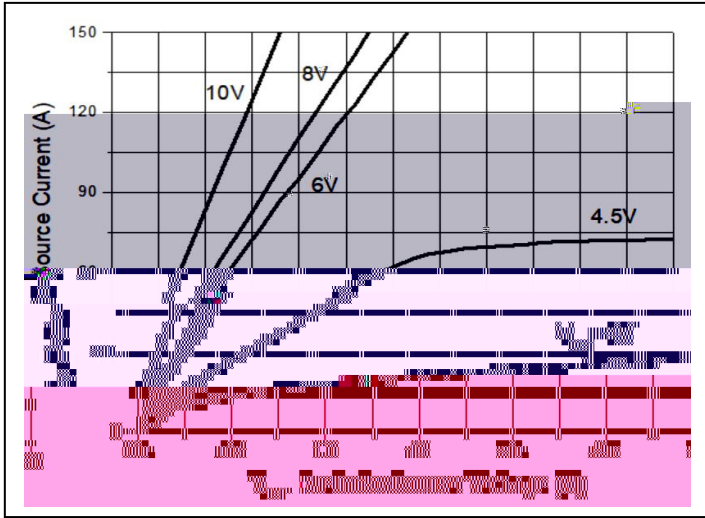


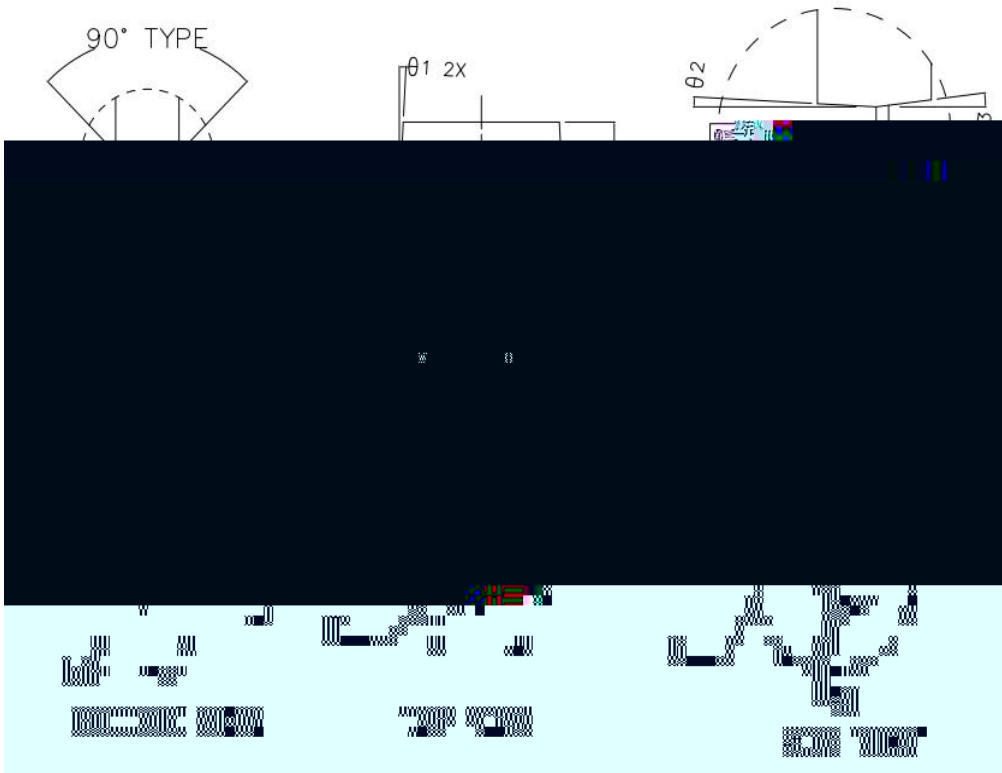


Calculated continuous current based on maximum allowable junction temperature.

Repetitive rating; pulse width limited by max. junction temperature.

The power dissipation P_D is based on max. junction temperature, using junction-to-case thermal resistance.





COMMON DIMENSIONS (UNITS OF MEASURE IS mm)			
	MIN	NORMAL	MAX
A1	0.020	0.100	0.200
A2	4.470	4.570	4.670
A3	2.30 ^{MIN}	2.35 ^{MIN}	2.400
b1	0.750	0.800	0.850
b2	1.220	1.270	1.320
c1	0.450	0.500	0.550
c2	1.250	1.300	1.350
D	9.900	10.000	10.100
▲D1	9.780	9.880	9.980
▲D2	7.900	8.000	8.100
E	14.900	15.100	15.300
▲E1	9.000	9.100	9.200
▲E2	7.600	7.700	7.800
e	2.540 TYPE		
L	2.100	2.300	2.500
L2	1.100	1.200	1.300
L3	1.300	1.500	1.700
▲L4	2.50 TYPE		
θ1	3° TYPE		
θ2	3° TYPE		
θ3	7° TYPE		
θ4	7° TYPE		
θ	0 ~ 8°		

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